

AMENDMENTS TO THE CLAIMS

The following listing of claims will replace all prior versions, and listings, of claims in the application.

1. (Currently Amended) A system that visually monitors semiconductor processing, comprising:
 - a develop chamber; ~~and~~
 - an image collector located at least partially within the develop chamber, the image collector collects energy reflected from inside the develop chamber and transmits a signal indicative of interior of the chamber; and
 - a controller that receives at least one sensor signal and selectively controls operation of the image collector in response to the received at least one sensor signal.
2. (Previously Presented) The system of claim 1 further includes a light source that illuminates the interior of the develop chamber to enable the image collector to obtain a visible image of the interior of the chamber.
3. (Previously Presented) The system of claim 2, the light source is a light emitting diode.
4. (Previously Presented) The system of claim 2, the light source is a fiber optic cable with a light emitting portion located within the develop chamber.
5. (Previously Presented) The system of claim 2, further comprises a coater chamber that provides photoresist material on a substrate, the light source provides light at a wavelength so as not to expose the photoresist material.
6. (Previously Presented) The system of claim 2, the develop chamber develops photoresist material on a substrate, the light source provides light at a wavelength so as not to expose the photoresist material.

7. (Previously Presented) The system of claim 2, the image collector includes a camera module that collects the images and provides an electrical signal indicative of a visual representation of the interior of the chamber.
8. (Previously Presented) The system of claim 7, the camera module is connected with one end of a fiber optic cable, a lens being connected with another end of the fiber optic cable for collecting the images from the interior of the chamber and providing the image signal to the camera module, the camera module converting the image signal into the electrical signal.
9. (Previously Presented) The system of claim 8, the lens is faceted to receive reflected light from a plurality of discrete directions within the chamber so that the image signal is formed of an image from each of the discrete directions.
10. (Previously Presented) The system of claim 7 further includes a viewing station that receives the electrical signal and displays a visual representation of the interior of the chamber according to the electrical signal.
11. (Previously Presented) The system of claim 10, the viewing station includes a controller that selectively controls activation of the camera module.
12. (Previously Presented) The system of claim 11, the controller further controls the light source.
13. (Previously Presented) The system of claim 1, the image collector includes a fiber optic cable having a light receiving end disposed within the chamber for collecting images of the interior of the chamber, another end of the fiber optic cable being connected to a camera module that provides the image signal indicative of the interior of the chamber, the camera module converting the image signal into an electrical signal indicative of the interior of the chamber.
14. (Previously Presented) The system of claim 13, the light receiving end of the fiber optic camera includes a lens for receiving light from a plurality of discrete directions within the chamber so that the image signal is formed of an image from each of the discrete directions.

15. (Currently Amended) A system that visually monitors an internal part of a semiconductor processing system, comprising:

imaging means for collecting images of an interior of an enclosed developer and providing an image signal indicative of a visual representation of the interior of the developer;

controller means for selectively controlling operation of the imaging means based on a received sensor signal; and

viewing means for receiving the image signal and providing a visual representation of the interior of the chamber.

16. (Previously Presented) The system of claim 15, the imaging means includes a camera having a lens portion located within the chamber to collect the images and provide the image signal.

17. (Previously Presented) The system of claim 15 further includes illumination means for illuminating the interior of the chamber to facilitate collecting images of the interior of the chamber by the camera.

18. (Previously Presented) The system of claim 17 further includes means for selectively controlling at least one of the camera and the illumination means.

19. (Currently Amended) A method for visually monitoring an interior of an enclosed developing chamber in a semiconductor processing system, comprising ~~the steps of:~~

controlling an operation based upon at least one signal indicative of an operating condition;

collecting visual images of the interior of the chamber and providing an image signal indicative thereof; and

displaying a visual representation of the interior of the enclosed chamber based on the image signal.

20. (Currently Amended) The method of claim 19 further comprising ~~includes the step of~~ illuminating the interior of the enclosed chamber to facilitate collecting of visual images.

21. (Currently Amended) The method of claim 20, ~~the step of~~ illuminating includes emitting light within the chamber at a wavelength which does not interfere with processing within the chamber.
22. (Currently Amended) The method of claim 19 further comprising ~~includes the step of~~ controlling the steps of emitting and collecting so that the visual representation includes images of processing within the chamber.
23. (Previously Presented) The method of claim 19, visual representation is displayed remotely from the semiconductor processing system.